

The documentation and process conversion measures necessary to comply with this amendment shall be completed by 14 October 2000.

INCH-POUND

MIL-PRF-19500/435E
AMENDMENT 1
14 July 2000

PERFORMANCE SPECIFICATION

SEMICONDUCTOR DEVICE, DIODE, SILICON, LOW-NOISE VOLTAGE REGULATOR TYPES
1N4099-1 THROUGH 1N4135-1, 1N4614-1 THROUGH 1N4627-1, 1N4099UR-1 THROUGH 1N4135UR-1,
1N4614UR-1 THROUGH 1N4627UR-1, PLUS C AND D TOLERANCE SUFFIX DEVICES
JAN, JANTX, JANTXV, JANJ, JANS, JANHC, AND JANKC

This amendment forms a part of MIL-PRF-19500/435E, dated 26 January 2000, and is approved for use by all Departments and Agencies of the Department of Defense.

PAGE 8

4.3, screen table, screen column 13; add "2".

4.3, note 2; delete and substitute:

" 2 PDA = 5 percent for screen 13, applies to ΔI_{R1} , ΔV_Z , I_{R1} and V_Z ."

PAGE 9

4.3.2, first sentence; delete " $I_Z = 50$ percent of column 10" and substitute " $I_Z =$ column 10".

PAGE 10

4.4.4, subgroup E4, conditions column; delete "Surface mount".

PAGE 12

4.5.7 Noise density; delete "4.5.7" and substitute "4.5.6".

PAGE 13

TABLE I, subgroup 4, inspection column, Noise density; delete "(see 4.5.7)" and substitute "(see 4.5.6)".

TABLE I, subgroup 7, conditions column, delete and substitute:

" $I_Z = 250 \mu\text{A dc}$; $T_1 = +25^\circ\text{C}$, $\pm 5^\circ\text{C}$; $T_2 = T_1 + 100^\circ\text{C}$."

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TABLE II, column 7 for 1N4105-1 through 1N4109-1; delete "0.5" five places, and substitute "0.05" five places.

PAGE 15

TABLE II, column 3 for 1N4113-1; delete "5.0" and substitute "2.5".

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Custodians:

Army - CR
Navy - EC
Air Force - 11
NASA - NA
DLA - CC

Preparing activity:
DLA - CC

(Project 5961-2283)

Review activities:

Army - AR, AV, MI, SM
Air Force - 19, 70, 80, 99
Navy - AS, CG, MC